


<b>Search Notes</b> 	<b>Application No.</b>	<b>Applicant(s)</b>	
	09/785,044	ILIFF, EDWIN C.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Joon H. Hwang	2162	

SEARCHED			
Class	Subclass	Date	Examiner
707	1-10	4/1/2005	<i>[Signature]</i>
707	100-104.1	4/1/2005	<i>[Signature]</i>
600	300	4/1/2005	<i>[Signature]</i>

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Palm EAST & WEST (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM TDB) ACM IEEE	4/1/2005	<i>[Signature]</i>